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| SERIAL NUMBER 09/881,445 | FILING DATE 06/13/2001 RULE | CLASS 438 | GROUP ART UNIT 2818 | ATTORNEY DOCKET NO. 4641-59261 |
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APPLICANTS

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**** CONTINUING DATA ******* *Verified and*
This application is a DIV of 09/316,082 05/20/1999 PAT 6,271,047

**** FOREIGN APPLICATIONS ******* *Verified and*
JAPAN 10-140292 05/21/1998
JAPAN 10-150963 06/01/1998
JAPAN 10-250071 09/03/1998
JAPAN 10-289175 10/12/1998
JAPAN 11-047485 02/25/1999

IF REQUIRED, FOREIGN FILING LICENSE GRANTED
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| Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no | STATE OR COUNTRY JAPAN | SHEETS DRAWING 10 | TOTAL CLAIMS 16 | INDEPENDENT CLAIMS 3 |
| 35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance | | | | |
| Verified and Acknowledged <i>MJM</i> Examiner's Signature Initials | | | | |

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TITLE
Layer-thickness detection methods and apparatus for wafers and the like, and polishing apparatus comprising same